

Short Course on Microwave Measurements For Digital Communication Systems

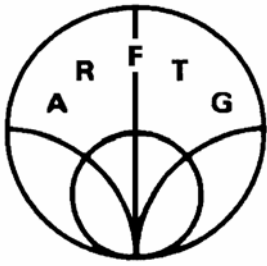
Nov. 29 – 30, 2005
Washington, D.C.



PRELIMINARY AGENDA

Tuesday, November 29

- 7:30 a.m. – 8:00 a.m. **Registration**
- 8:00 a.m. – 9:15 a.m. **VNA Error Models and Calibration Methods**
David Blackham – Agilent
- 9:15 a.m. – 9:50 a.m. **RF Connectors and Transmission Lines**
Ron Ginley – NIST
- 9:50 a.m. – 10:20 a.m. **Break**
- 10:20 a.m. – 11:00 a.m. **VNA Uncertainty**
Ron Ginley – NIST
- 11:00 a.m. – 12:15 p.m. **Microwave Power Measurements**
Tom Crowley – NIST
- 12:15 p.m. – 1:30p.m. **Lunch**
- 1:30 p.m. – 2:00 p.m. **Accurate On-Wafer Measurement**
Dave Walker & Dylan Williams - NIST
- 2:00 p.m. – 2:45 p.m. **Introduction to Materials Characterization**
Michael Janezic – NIST
- 2:45 p.m. – 3:05 p.m. **Break**
- 3:05 p.m. – 4:15 p.m. **Thermal Noise Measurements**
Jim Randa – NIST
- 4:15 p.m. – 5:15 p.m. **Digital Communication Systems Measurement**
Huseyin Arslan – University of South Florida



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NIST

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Wednesday, November 30

- 8:00 a.m. – 8:45 a.m. **Introduction to Optoelectronic Measurements**
Paul Hale – NIST
- 8:45 a.m. – 9:40 a.m. **Practical Oscilloscope Measurements**
Paul Hale/Tracy Clement – NIST
- 9:40 a.m. – 10:00 a.m. **Break**
- 10:00 a.m. – 12:00 p.m. **Large-Signal Network Analysis**
Jan Verspecht – Jan Verspecht bvba